


Search Notes 	Application/Control No. 10540670	Applicant(s)/Patent Under Reexamination CHANG, CHIN
	Examiner Rainey, Robert R	Art Unit 2629

SEARCHED			
Class	Subclass	Date	Examiner
340	815.45	12/12/2007	RR
345	691	12/12/2007	RR

SEARCH NOTES		
Search Notes	Date	Examiner
PLUS	11/01/2007	RR
QEM	11/06/2007	RR
QEM	12/12/2007	RR
EAST Search	12/12/2007	RR
Inventor Name Search PALM	12/12/2007	RR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner